

NON-CONVENTIONAL STRUCTURAL AND CHEMICAL CHARACTERISATIONS FOR THE INDUSTRY OF NANO-ELECTRONICS

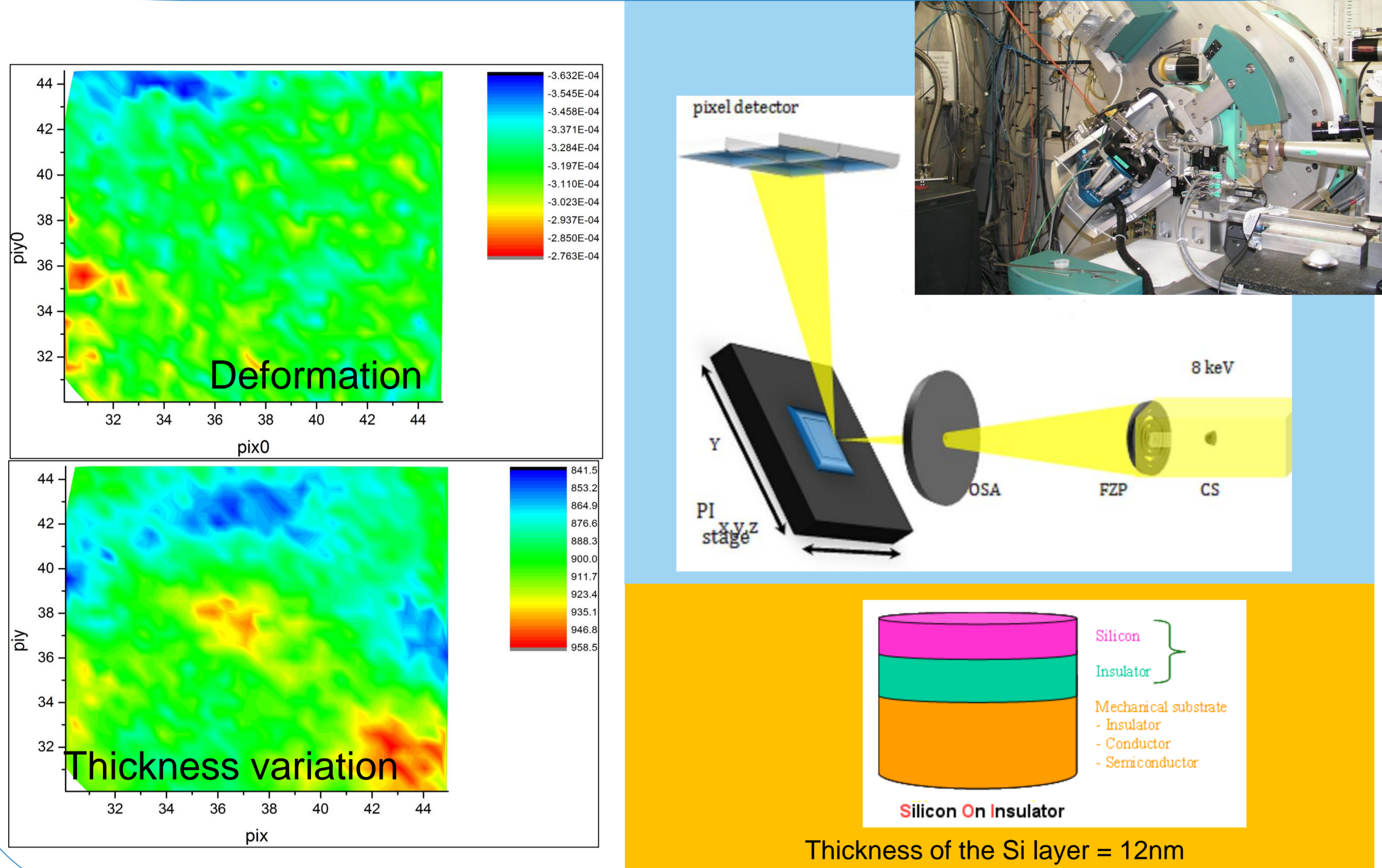
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Residual strain and thickness of thin layers



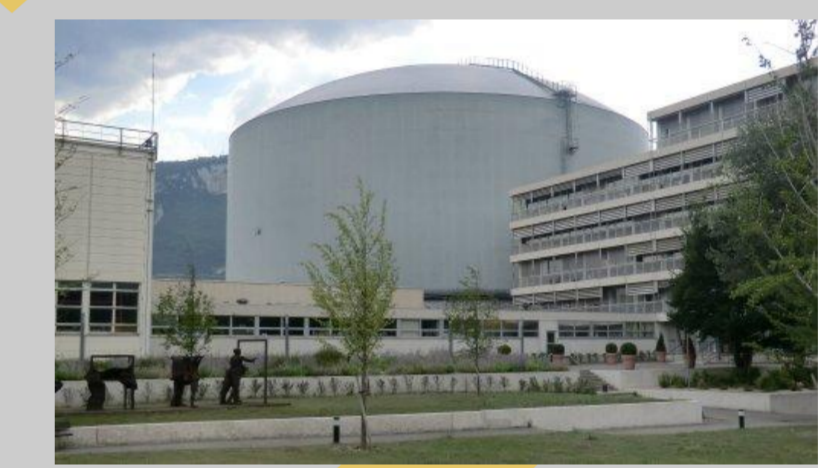
THE POWER OF LARGE SCALE RESEARCH INFRASTRUCTURES, SERVING INNOVATION

- THE MOST POWERFUL NEUTRONS SOURCE IN THE WORLD (ILL)
- ONE OF THE MOST BRILLIANT SYNCHROTRONS IN THE WORLD (ESRF)
- ULTIMATE NANO-CHARACTERISATION TOOLS FROM CEA (PFNC)

PFNC (CEA NanoCharacterisation platform)



Complementary characterisation
Sample preparation



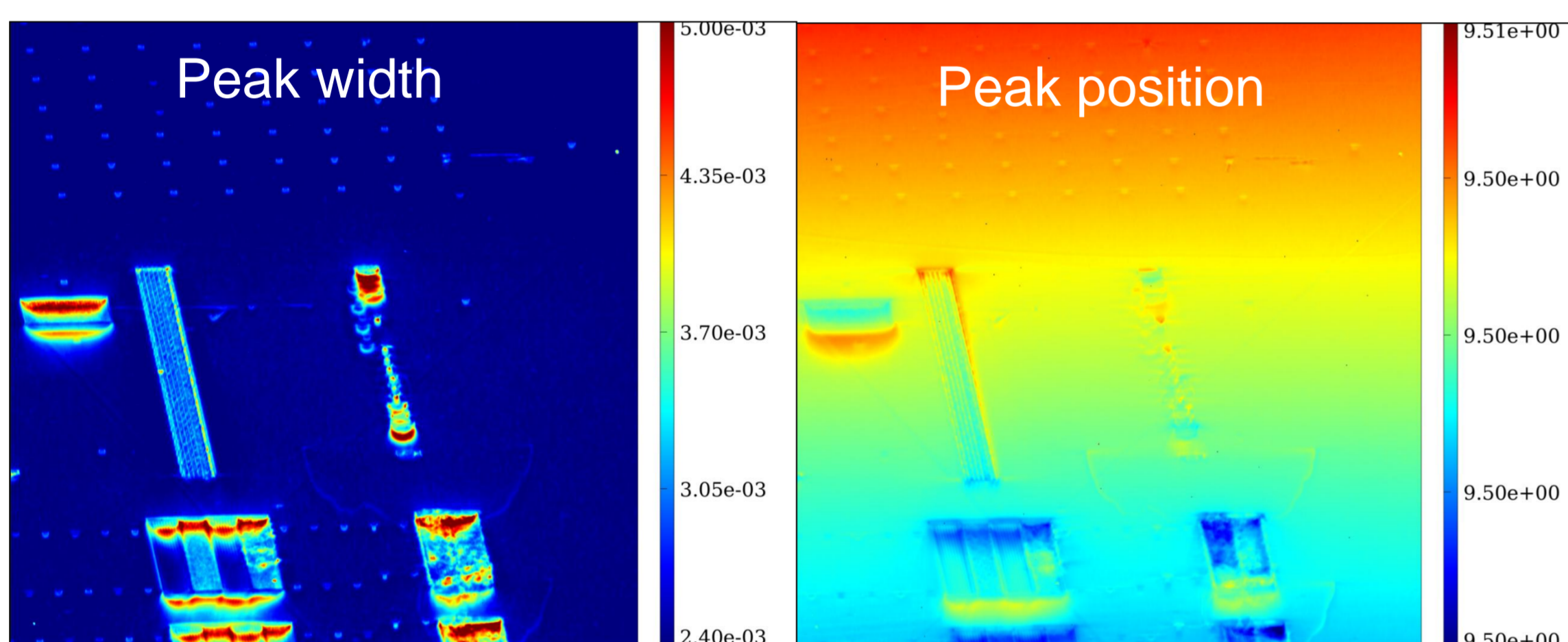
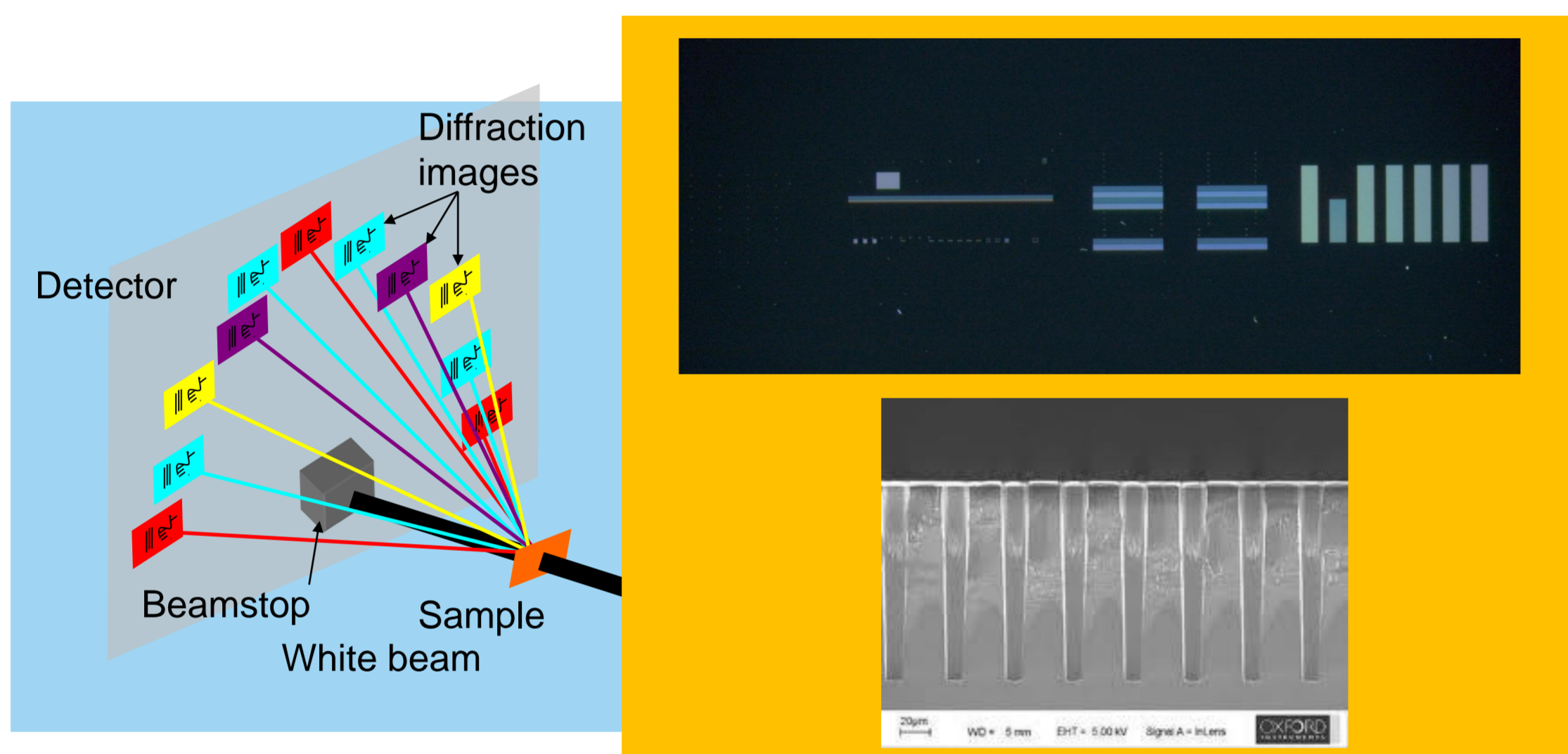
Synchrotron

Neutrons

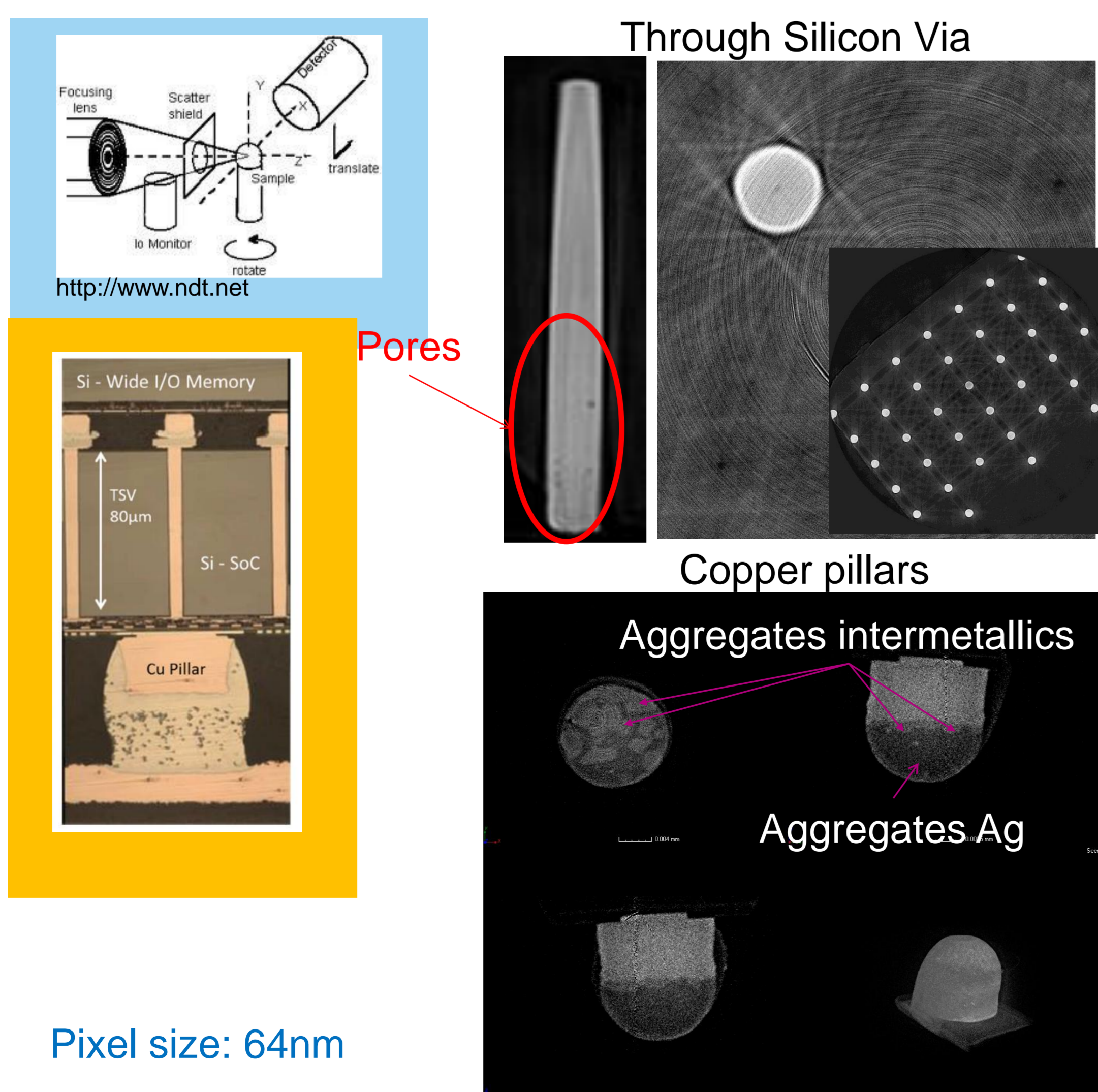


Detection

Dislocations in single crystals

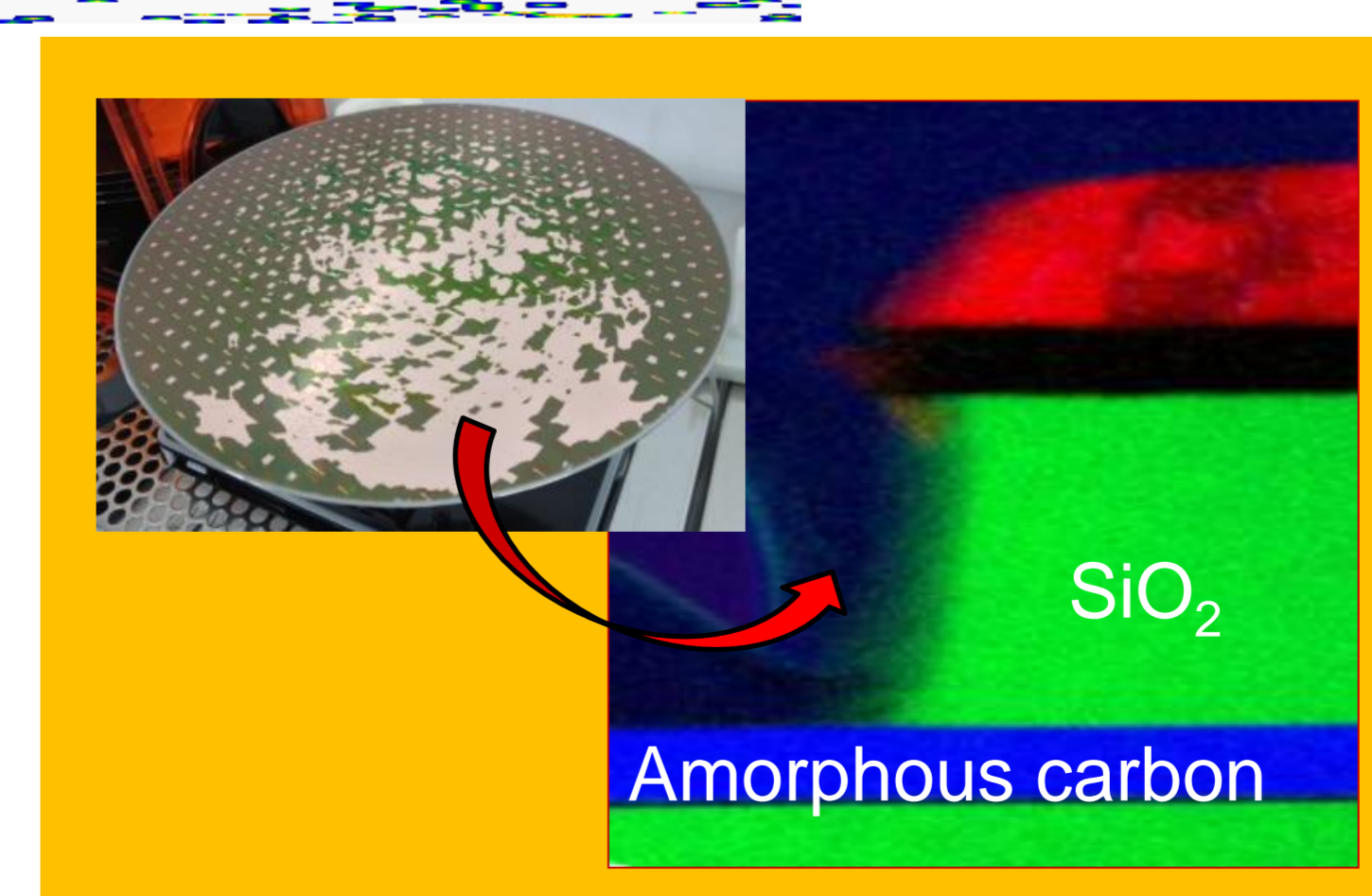
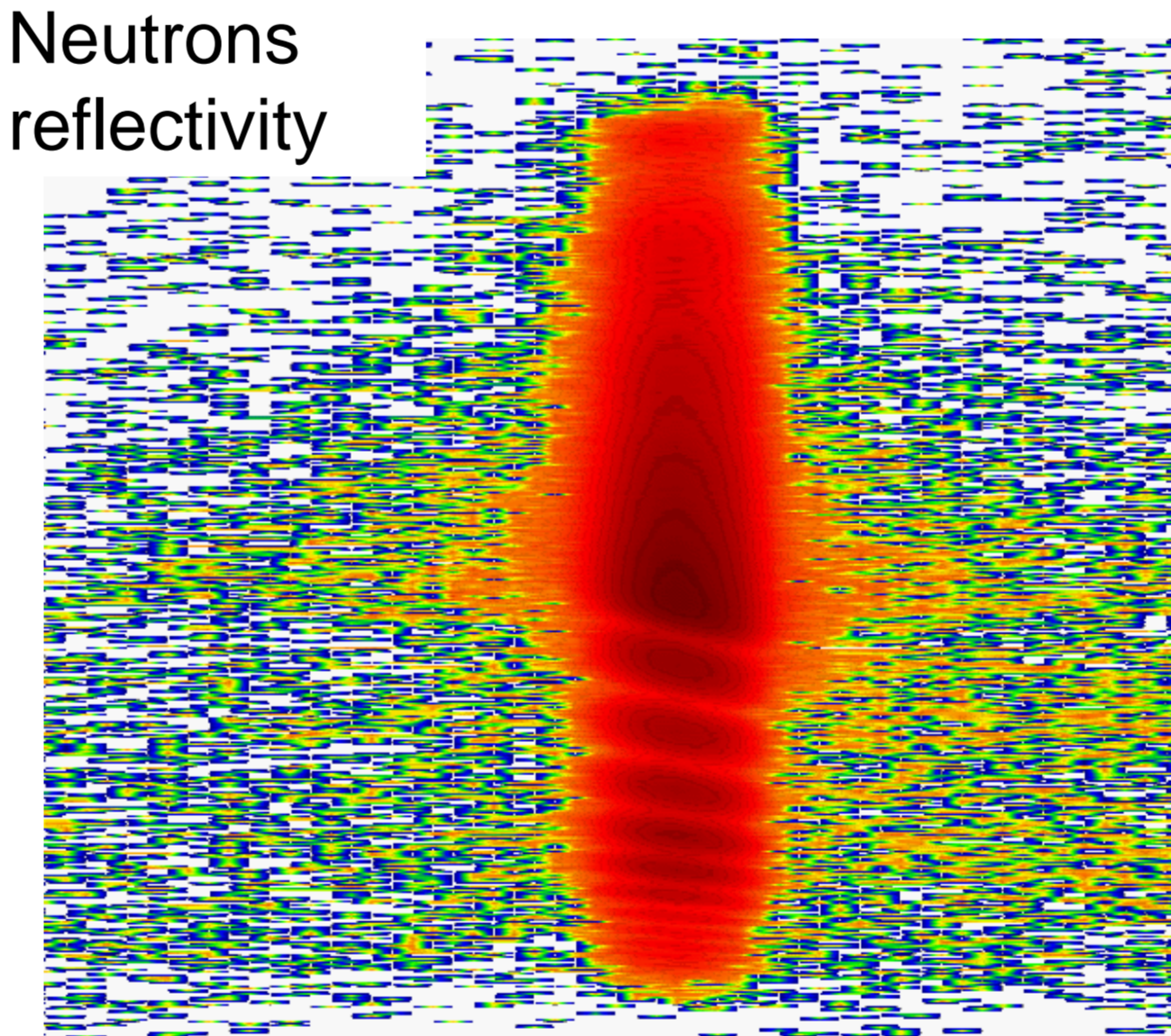


Defectology



Characterisation of bonding interfaces

Neutrons reflectivity



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